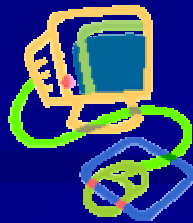


Comparison of  
IEEE Std 323-2003  
to  
IEC 60780 1998  
Jim Gleason, BSC  
IEEE SC-2.1



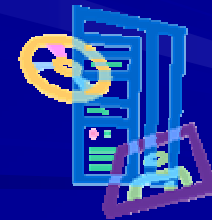
# Same

- Scope
- Qualified Life Definition
- Option Methods
  - Type Test
  - Operating Experience
  - Analysis



# Qualification Determination #1

- Given Environments are Enveloped
- Given Performance has been met
- Given Equipment Qualified to IEC 60780
- Equipment Also Qualified to IEEE Std 323-2003



# Qualification Determination #2

- Given Environments are Enveloped
- Given Performance has been met
- Given Equipment Qualified to IEEE Std 323-2003
- Equipment Also Qualified to IEC 60780



# Minor Differences

- IEEE Std 323-2003

- Harsh

- Mild

- IEC 60780 1998

- Format

- Group 1 Normal

- Group 2 Seismic

- Group 3 Accident & Post Accident



# Differences

- Two Transients = Margin
  - IEEE Std 323-1983 Concept; Never Accepted
- Corrosion Tests



# Conclusion

- No Major Philosophical Differences
- Allow IEC to Review IEEE Std 323-2003
- New in IEEE Std 323-2003
  - Condition Monitoring
  - EMI/RFI/Voltage Surges

